

<b>Notice of References Cited</b>	Application/Control No. 09/581,804	Applicant(s)/Patent Under Reexamination YOO ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,200,441 A	04-1993	Kim et al.	523/221
	B	US-5,225,494 A	07-1993	Ishiga, Narito	525/316
	C	US-5,071,946	12-1991	Schmidt et al.	528/306
	D	US-3,880,786	04-1975	Feast et al.	525/262
	E	US-3,855,355	12-1974	Moore, John David	525/316
	F	US-4,581,408	04-1986	Trabert et al.	525/66
	G	US-4,703,090	10-1987	Ferraresi et al.	525/246
	H	US-4,520,165	05-1985	Zabrocki et al.	525/84
	I	US-6,080,815 A	06-2000	Lee et al.	525/66
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 00/26298 A1	11-2000	International	Yoo et al.	C08L 33/06
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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